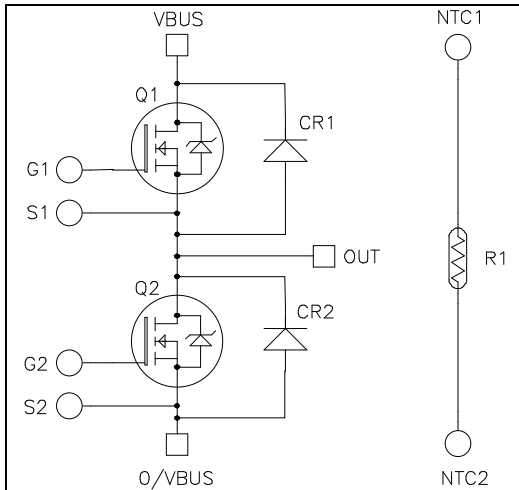


**Very low stray inductance  
Phase leg SiC MOSFET Power Module**

**$V_{DSS} = 1700V$**   
 **$R_{DS(on)} = 2.9m\Omega$  typ @  $T_j = 25^\circ C$**   
 **$I_D = 676A$  @  $T_c = 25^\circ C$**



### Application

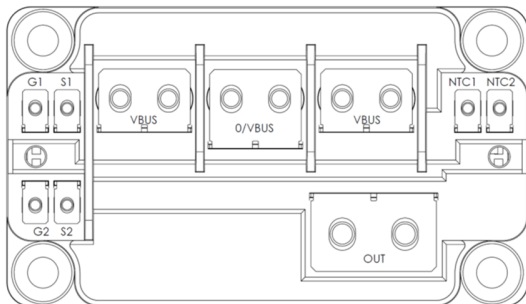
- Welding converters
- Switched Mode Power Supplies
- Uninterruptible Power Supplies
- EV motor and traction drive

### Features

- **SiC Power MOSFET**
  - Low  $R_{DS(on)}$
  - High temperature performance
- **SiC Schottky Diode**
  - Zero reverse recovery
  - Zero forward recovery
  - Temperature Independent switching behavior
  - Positive temperature coefficient on VF
- Very low stray inductance
- Internal thermistor for temperature monitoring
- M4 & M5 power connectors
- M2.5 signals connectors
- AlN substrate for improved thermal performance

### Benefits

- High efficiency converter
- Outstanding performance at high frequency operation
- Direct mounting to heatsink (isolated package)
- Low junction to case thermal resistance
- Low profile
- RoHS Compliant



**All ratings @  $T_j = 25^\circ C$  unless otherwise specified**

### Absolute maximum ratings (per SiC MOSFET)

Symbol	Parameter	Max ratings	Unit
$V_{DSS}$	Drain - Source Voltage	1700	V
$I_D$	Continuous Drain Current	$T_c = 25^\circ C$	676
		$T_c = 80^\circ C$	538
$I_{DM}$	Pulsed Drain current	1350	A
$V_{GS}$	Gate - Source Voltage	-10/23	V
$R_{DS(on)}$	Drain - Source ON Resistance	3.75	m $\Omega$
$P_D$	Power Dissipation	$T_c = 25^\circ C$ 3000	W

CAUTION: These Devices are sensitive to Electrostatic Discharge. Proper Handling Procedures Should Be Followed.

**Electrical Characteristics** (Per SiC MOSFET)

<i>Symbol</i>	<i>Characteristic</i>	<i>Test Conditions</i>	<i>Min</i>	<i>Typ</i>	<i>Max</i>	<i>Unit</i>
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{GS} = 0V, V_{DS} = 1700V$		120	1200	$\mu A$
$R_{DS(on)}$	Drain – Source on Resistance	$V_{GS} = 20V$ $I_D = 360A$	$T_j = 25^\circ C$	2.9	3.75	m $\Omega$
			$T_j = 175^\circ C$	5.1		
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS} = V_{DS}, I_D = 30 mA$	1.8	3.3		V
$I_{GSS}$	Gate – Source Leakage Current	$V_{GS} = 20 V, V_{DS} = 0V$			1200	nA

**Dynamic Characteristics** (Per SiC MOSFET)

<i>Symbol</i>	<i>Characteristic</i>	<i>Test Conditions</i>	<i>Min</i>	<i>Typ</i>	<i>Max</i>	<i>Unit</i>
$C_{iss}$	Input Capacitance	$V_{GS} = 0V$		39.6		nF
$C_{oss}$	Output Capacitance	$V_{DS} = 1000V$		1.8		
$C_{rss}$	Reverse Transfer Capacitance	$f = 1MHz$		0.12		
$Q_g$	Total gate Charge	$V_{GS} = -5/20V$		2136		nC
$Q_{gs}$	Gate – Source Charge	$V_{Bus} = 850V$		588		
$Q_{gd}$	Gate – Drain Charge	$I_D = 360A$		324		
$T_{d(on)}$	Turn-on Delay Time	$V_{GS} = -5/20V ; V_{Bus} = 900V$ $I_D = 600A ; T_j = 150^\circ C$ $R_G = 0.25\Omega$		65		ns
$T_r$	Rise Time			52		
$T_{d(off)}$	Turn-off Delay Time			148		
$T_f$	Fall Time			44		
$E_{on}$	Turn on Energy	$V_{GS} = -5/+20V$ $V_{Bus} = 900V ; I_D = 600A$	$T_j = 150^\circ C$	23		mJ
$E_{off}$	Turn off Energy	$R_G = 0.25\Omega$	$T_j = 150^\circ C$	10.7		
$R_{Gint}$	Internal gate resistance			0.79		$\Omega$
$R_{thJC}$	Junction to Case Thermal Resistance				0.05	$^\circ C/W$

**Body diode ratings and characteristics** (Per SiC MOSFET)

<i>Symbol</i>	<i>Characteristic</i>	<i>Test Conditions</i>	<i>Min</i>	<i>Typ</i>	<i>Max</i>	<i>Unit</i>
$V_{SD}$	Diode Forward Voltage	$V_{GS} = 0V, I_{SD} = 360A$		3.7		V
		$V_{GS} = -5V, I_{SD} = 360A$		3.9		
$t_{rr}$	Reverse Recovery Time	$I_{SD} = 360A ; V_{GS} = -5V$ $V_R = 900V ; di_F/dt = 1200A/\mu s$		27		ns
$Q_{rr}$	Reverse Recovery Charge			7.8		$\mu C$
$I_{rr}$	Reverse Recovery Current			552		A

**SiC diode characteristics (Per SiC diode)**

<i>Symbol</i>	<i>Characteristic</i>	<i>Test Conditions</i>		<i>Min</i>	<i>Typ</i>	<i>Max</i>	<i>Unit</i>
V <sub>RRM</sub>	Peak Repetitive Reverse Voltage					1700	V
I <sub>RRM</sub>	Reverse Leakage Current	V <sub>R</sub> =1700V	T <sub>j</sub> = 25°C		300	1200	μA
			T <sub>j</sub> = 175°C		1500		
I <sub>F</sub>	Forward Current		T <sub>c</sub> = 125°C		300		A
V <sub>F</sub>	Diode Forward Voltage	I <sub>F</sub> = 300A	T <sub>j</sub> = 25°C		1.5	1.8	V
			T <sub>j</sub> = 175°C		2		
Q <sub>C</sub>	Total Capacitive Charge	V <sub>R</sub> = 900V			2460		nC
C	Total Capacitance	f = 1MHz, V <sub>R</sub> = 600V			1800		pF
		f = 1MHz, V <sub>R</sub> = 900V			1500		
R <sub>thJC</sub>	Junction to Case Thermal Resistance					0.062	°C/W

**Package characteristics**

<i>Symbol</i>	<i>Characteristic</i>	<i>Min</i>	<i>Max</i>	<i>Unit</i>		
V <sub>ISOL</sub>	RMS Isolation Voltage, any terminal to case t=1 min, 50/60Hz	4000		V		
T <sub>J</sub>	Operating junction temperature range	-40	175	°C		
T <sub>JOP</sub>	Recommended junction temperature under switching conditions	-40	T <sub>Jmax</sub> -25			
T <sub>STG</sub>	Storage Temperature Range	-40	125			
T <sub>C</sub>	Operating Case Temperature	-40	125			
Torque	Mounting torque	For terminals	M2.5	0.4	0.6	N.m
			M4	2	3	
			M5	2	3.5	
		To heatsink	M6	3	5	
L <sub>DC</sub>	Module stray inductance between VBUS & 0/VBUS		3	nH		
Wt	Package Weight		320	g		

**Temperature sensor NTC** (see application note APT0406).

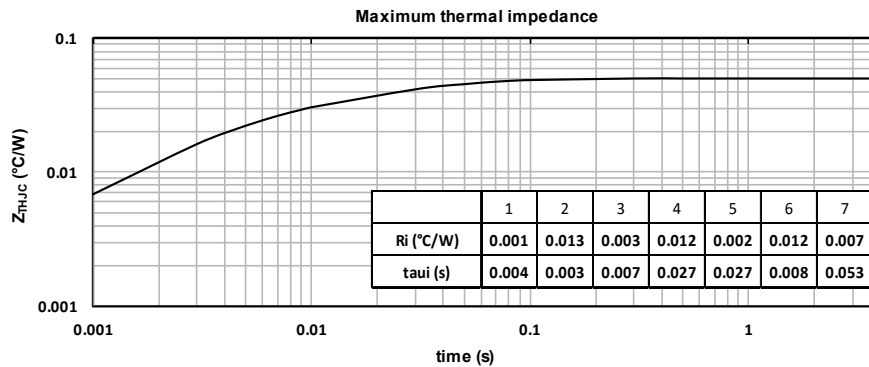
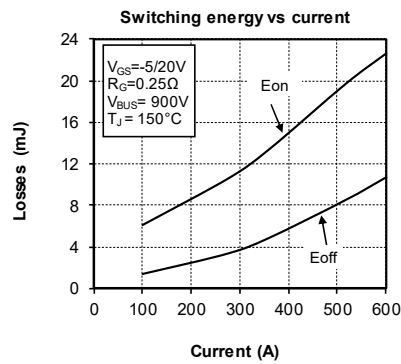
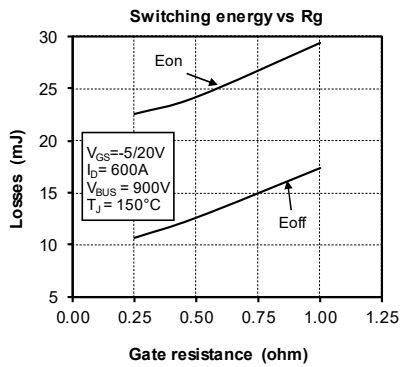
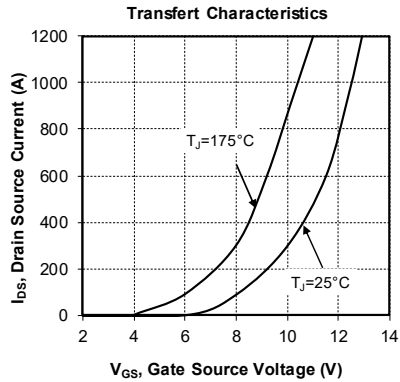
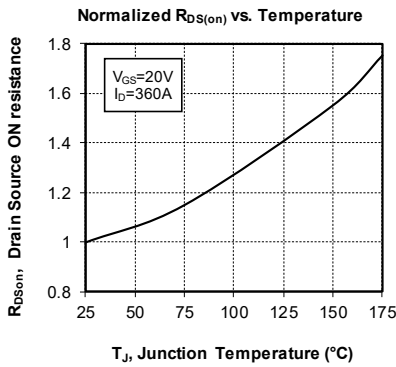
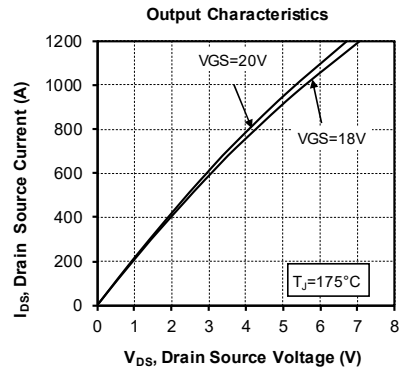
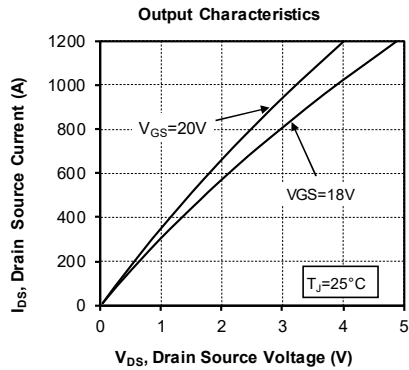
<i>Symbol</i>	<i>Characteristic</i>	<i>Min</i>	<i>Typ</i>	<i>Max</i>	<i>Unit</i>
R <sub>25</sub>	Resistance @ 25°C		50		kΩ
ΔR <sub>25</sub> /R <sub>25</sub>			5		%
B <sub>25/85</sub>	T <sub>25</sub> = 298.15 K		3952		K
ΔB/B	T <sub>C</sub> =100°C		4		%

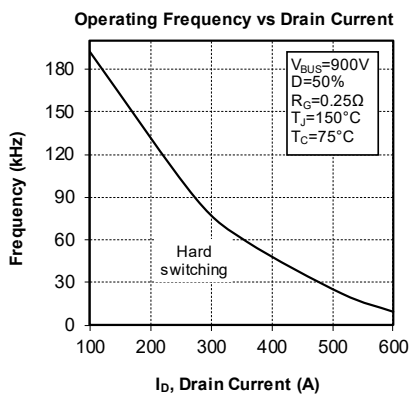
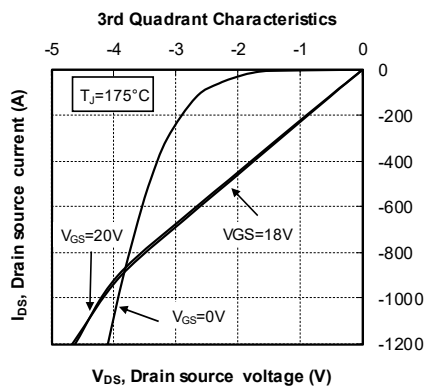
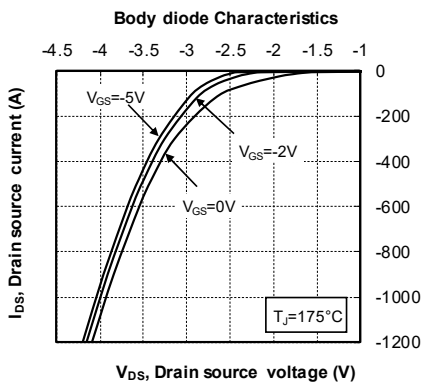
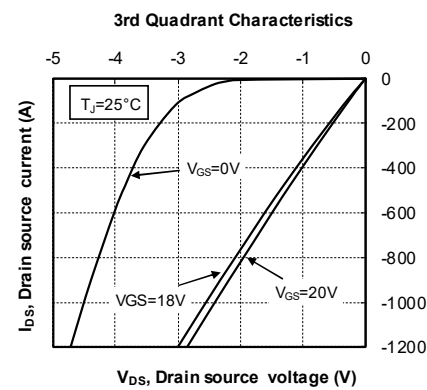
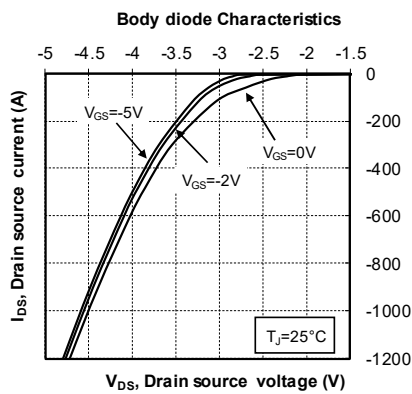
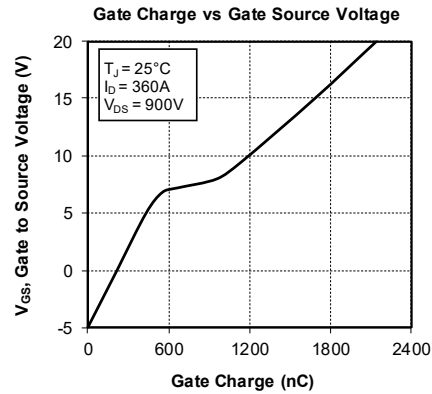
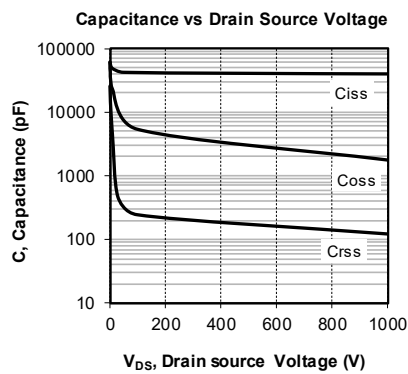
$$R_T = \frac{R_{25}}{\exp\left[B_{25/85}\left(\frac{1}{T_{25}} - \frac{1}{T}\right)\right]}$$

T: Thermistor temperature  
R<sub>T</sub>: Thermistor value at T



### Typical SiC MOSFET Performance Curve





**Typical SiC diode Performance Curve**
